SN5412, SN54LS12 SN7412, SN74LS12

SDLS040 TRIPLE 3-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

DECEMBER 1983-REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

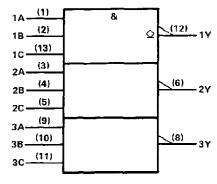
These devices contain three independent 3-input NAND gates with open-collector outputs. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher VOH levels.

The SN5412 and SN54LS12 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN7412 and SN74LS12 are characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate)

	VPUT	s	OUTPUT
Д	В	¢	Y
Н	Н_	н	L
L	Х	x	н
x	L	x	н
х	Х	L	H

logic symbol[†]



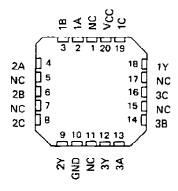
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

SN5412, SN54LS12...J OR W PACKAGE SN7412...N PACKAGE SN74LS12...D OR N PACKAGE (TOP VIEW)

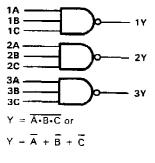
1A	Пī	U14	VCC
1B	2	13	1C
2A	□3	12	1Y
2B	□₄	11	3C
2C	₫5	10	3B
2Y	□ 6	Дe	3A
GND	□ 7	8	3Y

SN54LS12 . . . FK PACKAGE (TOP VIEW)



NC-No internal connection

logic diagram (positive logic)



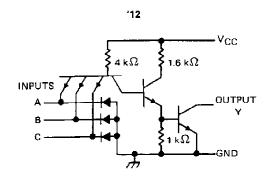
PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



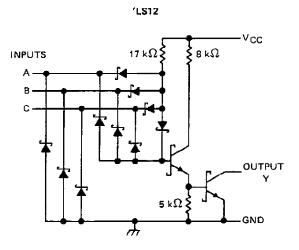
SN5412, SN54LS12 SN7412, SN74LS12

TRIPLE 3-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR DUTPUTS

schematics (each gate)







absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)
Input voltage: '12
'LS12
Off-state output voltage
Operating free-air temperature: SN54'
SN74' 0°C to 70°C
Storage temperature range

NOTE 1: Voltage values are with respect to network ground terminal.



SN5412, SN5412 TRIPLE 3 INPUT POSITIVE NAND GATES WITH OPEN COLLECTOR OUTPUTS

recommended operating conditions

		SN5412			SN7412			
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
V _{CC} Supply voltage	4.5	5	5,5	4.75	5	5,25	V	
VIH High-level input voltage	2			2		·	V	
V _{IL} Low-level input voltage			0.8			8.0	V	
VOH High-level output voltage			5.5			5,5	V	
IOL Low-level output current			16			16	mA	
TA Operating free-air temperature	– 55		125	0		70	∘c	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN5412	SN7412	
PARAMETER	TEST CONDITIONS.	MIN TYPI MAX	MIN TYPI MAX	UNIT
Vik	VCC = MIN, II = -12 mA	-1.5	- 1.5	٧
la.	$V_{CC} = MIN$, $V_{IL} = 0.8 \text{ V}$, $V_{OH} = 5.5 \text{ V}$		0.25	4
IOH	$V_{CC} = MIN$, $V_{IL} = 0.7 \text{ V}$, $V_{OH} = 5.5 \text{ V}$	0.25		mA
VOL	VCC = MIN, VIH = 2 V, IOL = 16 mA	0.2 0.4	0.2 0.4	٧
l _l	V _{CC} = MAX, V _I = 5.5 V	1	1	mΑ
lн	$V_{CC} = MAX$, $V_1 = 2.4 V$	40	40	μΑ
lii.	$V_{CC} = MAX$, $V_I = 0.4 V$	-1.6	-1.6	mA
ССН	$V_{CC} = MAX$, $V_I = 0$	3 6	3 6	mA
CCL	$V_{CC} = MAX$, $V_{\parallel} = 4.5 V$	9 16.5	9 16.5	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, VCC = 5 V, TA = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
tPLH	A, B or C	· ·	R _L = 4 k(),	C _L = 15 pF		35	45	nş
^t ₽H L	I I	<u>'</u>	R _L = 400 Ω,	C _L = 15 pF		8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



 $^{^{\}ddagger}$ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

SN54LS12, SN74LS12 TRIPLE 3-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

		SN54LS12			\$N74LS12			
	MIN	NOM	MAX	MIN	NOM	MAX	דומט	
VCC Supply voltage	4.5	5	5,5	4.75	5	5.25	V	
VIH High-level input voltage	2			2			٧	
VIL - Low-level input voltage			0.7			0.8	V	
V _{OH} High-level output voltage			5.5			5.5	٧	
IOL Low-level output current			4			8	mΑ	
TA Operating free-air temperature	– 55		125	0		70	°c	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			SN54LS12			SN74LS12				
		TEST CONDITIONS †		MIN	TYP‡	MAX	MIN	TYP\$	MAX	UNIT
VIK	V _{CC} = MIN,	I ₁ = - 18 mA				- 1.5			- 1.5	٧
^I ОН	V _{CC} = MIN,	VIL = MAX,	V _{OH} = 5.5 V			0.1			0.1	πА
	V _{CC} = MIN,	V _{1H} = 2 V,	1 _{OL} = 4 mA		0.25	0.4		0.25	0.4	V
VOL	V _{CC} = MIN,	V _{IH} = 2 V,	I _{OL} = 8 mA					0.35	0.5	
11	V _{CC} = MAX,	V = 7 V				0.1			0.1	mA
Чн	V _{CC} = MAX,	V _I = 2.7 V				20		·	20	μА
l _{IL}	V _{CC} = MAX,	V = 0.4 V				- 0.4			- 0.4	mA
ICCH	V _{CC} = MAX,	VI = 0			- 0.7	1.4		0,7	1.4	mA
¹ CCL	V _{CC} = MAX,	V _I = 4.5 V			1,8	3.3		1.8	3,3	mΑ

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. ‡ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

switching characteristics, VCC = 5 V, TA = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN TYP	MAX	UNIT
tPLH	A, B or C	· ·	R _L = 2 kΩ, C _L = 15 pF	17	32	ns
tPHL_		•	Mg = 2 km², Sg + 15 pr	15	28	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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